TOSHIBA Photocoupler GaAs Ired & Photo-Transistor

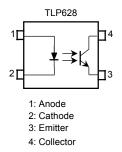
TLP628,TLP628-2,TLP628-4

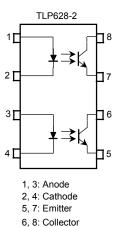
Programmable Controllers DC-Output Module Telecommunication

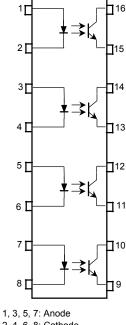
The TOSHIBA TLP628, -2, and -4 consists of a gallium arsenide infrared emitting diode optically coupled to a phototransistor which has a 350V high voltage of collector-emitter breakdown voltage. The TLP628-2 offers two isolated channels in a eight lead plastic DIP package, while the TLP628-4 provide four isolated channels per package.

- Collector-emitter voltage: 350 V (min.)
- Current transfer ratio: 50% (min.)
- Isolation voltage: 5000Vrms (min.)
- UL recognized: UL1577, file No. E67349
- BSI approved: BS EN60065:2002, certificate no.7426 BS EN60950-1:2002, certificate no.7427

Pin Configurations (top view)

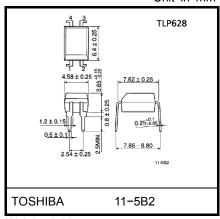




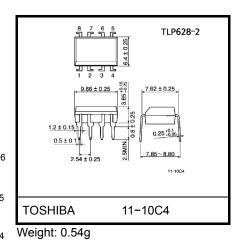


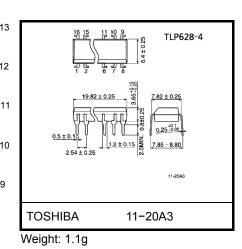
TLP628-4

2, 4, 6, 8: Cathode 9, 11, 13, 15: Emitter 10, 12, 14, 16: Collector









Unit in mm

Absolute Maximum Ratings (Ta = 25°C)

			Rat		
	Characteristic	Symbol	TLP628	TLP628–2 TLP628–4	Unit
	Forward current	١ _F	60	50	mA
	Forward current derating	ΔI _F / °C	–0.7 (Ta ≥ 39°C)	–0.5 (Ta ≥ 25°C)	mA / °C
LED	Pulse forward current	I _{FP}	1 (100µs pu	А	
[Reverse voltage	V _R	Ę	V	
	Junction temperature	Тj	12	°C	
	Collector-emitter voltage	V _{CEO}	35	V	
	Emitter-collector voltage	V _{ECO}	7	V	
for	Collector current	Ι _C	50		mA
Detector	Collector power dissipation (1 circuit)	P _C	150	100	mW
	Collector power dissipation derating (Ta ≥ 25°C, 1 circuit)	ΔP _C / °C	-1.5	-1.0	mW / °C
	Junction temperature	Тj	12	°C	
Stor	rage temperature range	T _{stg}	-55~125		°C
Ope	erating temperature range	T _{opr}	-55~100		°C
Lead soldering temperature		T _{sol}	260 (10s)		°C
Total package power dissipation (1 circuit)		PT	200 150		mW
Total package power dissipation derating (Ta ≥ 25°C, 1 circuit)		ΔP _T / °C	-2.0 -1.5		mW / °C
Isolation voltage		BVS	5000 (AC, 1min., R.H. ≤ 60%) (Note 1)		Vrms

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

(Note 1) Device considered a two terminal device: LED side pins shorted together and detector side pins shorted together.

Recommended Operating Conditions

Characteristic	Symbol	Min.	Тур.	Max.	Unit
Supply voltage	V _{CC}	—	—	200	V
Forward current	١ _F	—	16	25	mA
Collector current	ΙC	—	_	10	mA
Operating temperature	T _{opr}	-25		85	°C

Note: Recommended operating conditions are given as a design guideline to obtain expected performance of the device. Additionally, each item is an independent guideline respectively. In developing designs using this product, please confirm specified characteristics shown in this document.

Individual Electrical Characteristics (Ta = 25°C)

	Characteristic	Symbol	Test Condition	Min.	Тур.	Max.	Unit
LED	Forward voltage	VF	I _F = 10 mA	1.0	1.15	1.3	V
	Reverse current	I _R	V _R = 5 V	_	—	10	μA
	Capacitance	CT	V = 0, f = 1 MHz	_	30	_	pF
Detector	Collector–emitter breakdown voltage	V _(BR) CEO	I _C = 0.1 mA	350	_		V
	Emitter–collector breakdown voltage	V _{(BR) ECO}	I _E = 0.1 mA	7	_	_	V
	Collector dark current	1000	V _{CE} = 300 V	_	10	200	nA
		ICEO	V _{CE} = 300 V, Ta = 85°C		_	50	μA
	Capacitance collector to emitter	C _{CE}	V = 0, f = 1 MHz	_	10	_	pF

Coupled Electrical Characteristics (Ta = 25°C)

Characteristic	Symbol	Test Condition	Min.	Тур.	Max.	Unit
Current transfer ratio	I _C / I _F	I _F = 5 mA, V _{CE} = 5 V Rank GB	50		600	%
			100		600	
Saturated CTR	I _C / I _{F (sat)}	IF = 1 mA, V _{CE} = 0.4 V Rank GB		60		%
			30			
Collector–emitter saturation voltage		I _C = 2.4 mA, I _F = 8 mA			0.4	
		I _C = 0.2 mA, I _F = 1 mA Rank GB	_	0.2	_	V
			-		0.4	

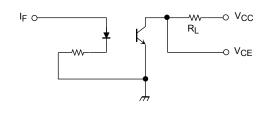
Isolation Characteristics (Ta = 25°C)

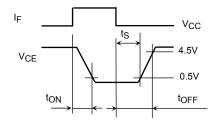
Characteristic	Symbol	Test Condition	Min.	Тур.	Max.	Unit
Capacitance input to output	CS	V _S = 0, f = 1 MHz	_	0.8	_	pF
Isolation resistance	R _S	V _S = 500 V R.H. ≤ 60%	5×10 ¹⁰	10 ¹⁴	_	Ω
		AC, 1 minute	5000	_		V
Isolation voltage	BVS	AC, 1 second, in oil	_	10000		V _{rms}
		DC, 1 minute, in oil	_	10000		V _{dc}

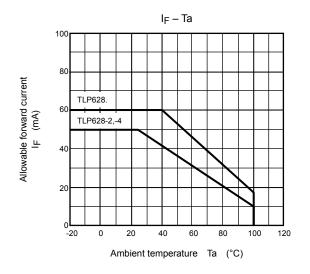
Switching Characteristics (Ta = 25°C)

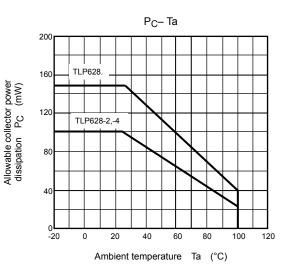
Characteristic	Symbol	Test Condition	Min.	Тур.	Max.	Unit
Rise time	tr		_	2	_	
Fall time	t _f	V _{CC} = 10 V, I _C = 2 mA	_	3	_	μs
Turn–on time	t _{on}	$AR_L = 100\Omega$		3	_	
Turn–off time	t _{off}			3	_	
Turn–on time	t _{ON}	R _L = 1.9 kΩ (Fig.1) V _{CC} = 5 V, I _F = 16 mA		3	_	
Storage time	ts		_	40	_	μs
Turn–off time	tOFF			90	_	

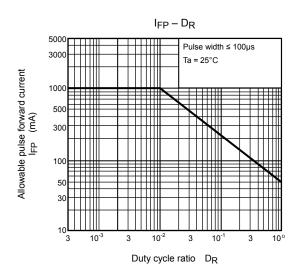
Fig. 1 Switching time test circuit

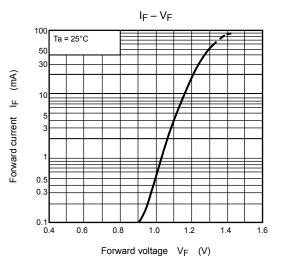


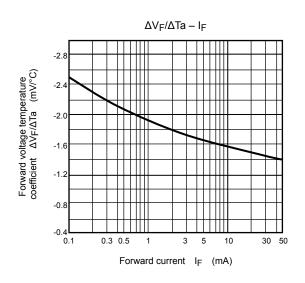


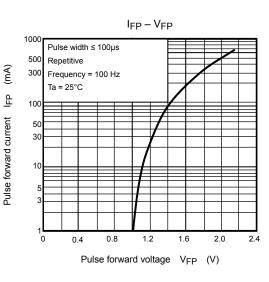




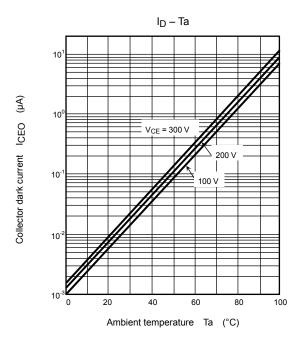


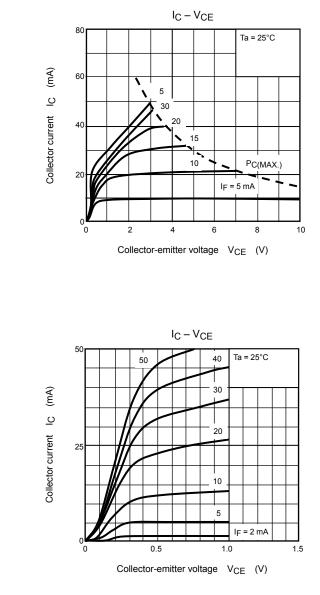


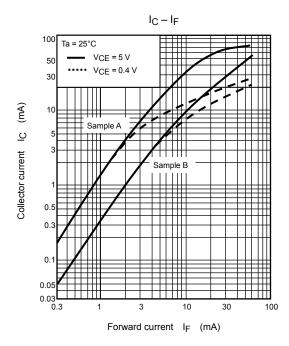


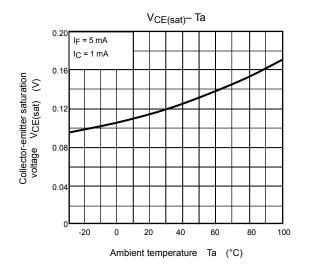


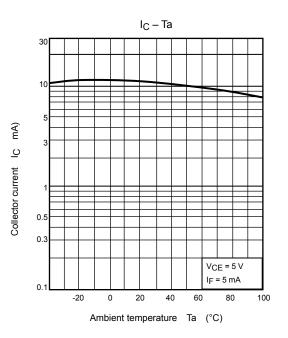
TOSHIBA

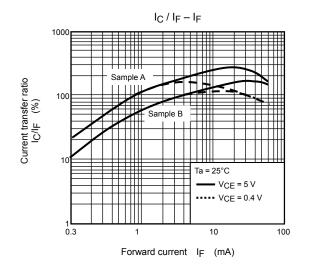




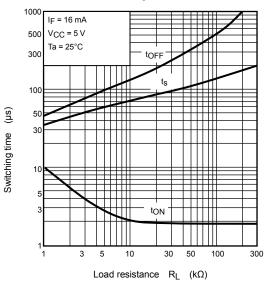








Switching Time – RL



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